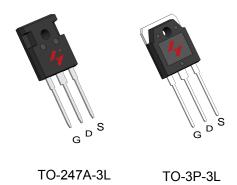


#### N-Channel Enhancement Mode MOSFET

#### **Features**

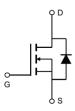
- 125V/300A  $R_{\rm DS(ON)} = 2.9 \, {\rm m} \, \Omega \ \ ({\rm typ.}) \, @ \, {\rm V_{GS}} = 10 {\rm V} \label{eq:constraint}$
- Avalanche Rated
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

### Pin Description



## **Applications**

Power Management for Inverter Systems.



N Channel MOSFET

## Ordering and Marking Information





Package Code

W : TO-247A-3L A : TO-3P-3L

Date Code Assembly Material
YYXXX WW G: Lead Free Device

Note: HUAYI lead -free products contain molding compounds/die attach materials and 100% matte tin plate Termination finish; which are fully compliant with RoHS. HUAYI lead -free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



# **Absolute Maximum Ratings**

Symbol	Parameter		Rating	Unit
Common	Ratings (T <sub>C</sub> =25°C Unless Otherwise Noted)			
V <sub>DSS</sub>	Drain-Source Voltage		125	V
V <sub>GSS</sub>	Gate-Source Voltage		±25	
TJ	Maximum Junction Temperature		175	°C
T <sub>STG</sub>	Storage Temperature Range		55 to 175	°C
Is	Diode Continuous Forward Current	T <sub>C</sub> =25°C	300	А
Mounted (	on Large Heat Sink	<u>.</u>		•
I <sub>DM</sub>	Pulsed Drain Current *	T <sub>C</sub> =25°C	1100**	А
	Continuous Proin Current	T <sub>C</sub> =25°C	300	^
l <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> =100°C	196	A
В	Maximum Bayyar Dissipation	T <sub>C</sub> =25°C	500	W
P <sub>D</sub>	Maximum Power Dissipation	T <sub>C</sub> =100°C	250	
$R_{\theta JC}$	Thermal Resistance-Junction to Case		0.3	°C // //
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient		40	°C/W
Avalanche	e Ratings			*
E <sub>AS</sub>	Avalanche Energy, Single Pulsed	L=0.5mH	2000***	mJ

Note: \* Repetitive rating; pulse width limited by junction temperature

# **Electrical Characteristics** $(T_c = 25^{\circ}C \text{ Unless Otherwise Noted})$

Cumbal	Parameter	Test Conditions		HY5012		Unit
Symbol	Farameter	Test Conditions	Min.	Тур.	Max.	Onit
Static Cha	aracteristics			*	,	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	125	-	-	V
	V <sub>DS</sub> =125V, V <sub>GS</sub> =0V		-	-	1	
I <sub>DSS</sub> Zero Gate Voltage Drain C	Zero Gate Voltage Drain Current	T <sub>J</sub> =85°C	-	-	10	μΑ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=250\mu A$	2	3	4	V
I <sub>GSS</sub>	Gate Leakage Current	$V_{GS}=\pm25V, V_{DS}=0V$	-	-	±100	nA
R <sub>DS(ON)</sub> *	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =150A	-	2.9	3.6	mΩ
Diode Cha	Diode Characteristics					
V <sub>SD</sub> *	Diode Forward Voltage	I <sub>SD</sub> =150 A, V <sub>GS</sub> =0V	-	0.8	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	1 150 A dl /dt 100 A /	-	70	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>SD</sub> =150 A, dI <sub>SD</sub> /dt=100A/ <sub>k</sub>	-	134	-	nC

<sup>\*\*</sup> Drain current is limited by junction temperature
\*\*\* VD=100V



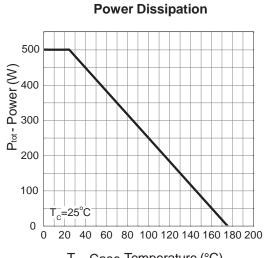
# **Electrical Characteristics (Cont.)** $(T_c = 25^{\circ}C \text{ Unless Otherwise Noted})$

Symbol	Parameter	Test Conditions	Н	HY5012		Unit
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Offic
Dynamic (	Characteristics					
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> =0V,V <sub>DS</sub> =0V,F=1MHz	-	0.5	-	Ω
C <sub>iss</sub>	Input Capacitance	$V_{GS}=0V$ ,	-	16300	-	
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V,	-	1570	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	Frequency=1.0MHz	-	930	-	
t <sub>d(ON)</sub>	Turn-on Delay Time	$V_{DD}$ =62.5 V, R <sub>G</sub> =6 $\Omega$ , $I_{DS}$ =150A, $V_{GS}$ =10V,	-	55	1	
Tr	Turn-on Rise Time		-	49	-	ns
t <sub>d(OFF)</sub>	Turn-off Delay Time		-	122	1	115
T <sub>f</sub>	Turn-off Fall Time		-	98	ı	
Gate Char	Gate Charge Characteristics					
Qg	Total Gate Charge		-	352	-	
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS}$ =100V, $V_{GS}$ =10V, $V_{DS}$ =150A	-	46	-	nC
$Q_{gd}$	Gate-Drain Charge	103	-	136	1	

Note \* : Pulse test ; pulse width  $\leq\!300\mu s,$  duty cycle  $\!\leq\!2\%.$ 



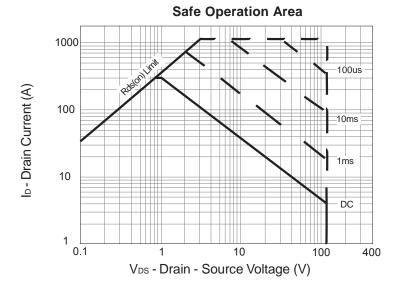
## **Typical Operating Characteristics**



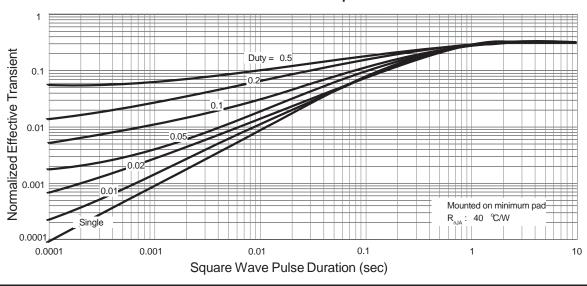
280 limited by package
240
200
160
120
80
T\_c=25°C,V\_c=10V
0 20 40 60 80 100 120 140 160 180 200

T<sub>c</sub>- Case Temperature (°C)

Tc-Case Temperature (°C)



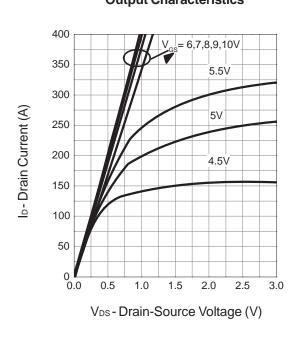
#### **Thermal Transient Impedance**



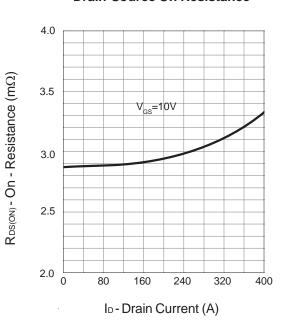


## **Typical Operating Characteristics (Cont.)**

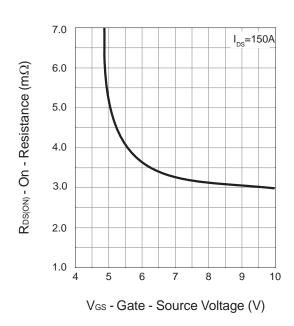
## **Output Characteristics**



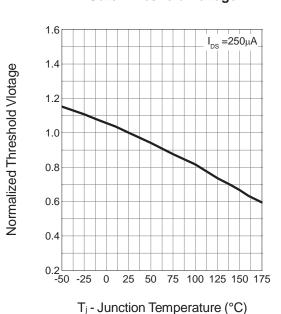
#### **Drain-Source On Resistance**



#### **Drain-Source On Resistance**



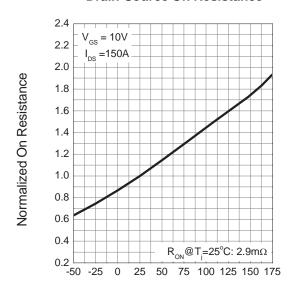
#### **Gate Threshold Voltage**





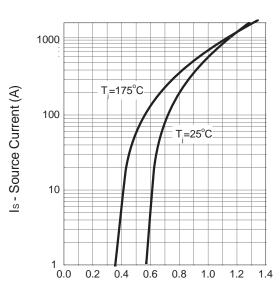
## **Typical Operating Characteristics (Cont.)**

## Drain-Source On Resistance



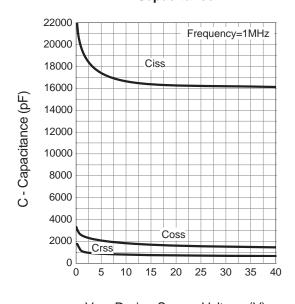
T<sub>j</sub>- Junction Temperature (°C)

#### Source-Drain Diode Forward



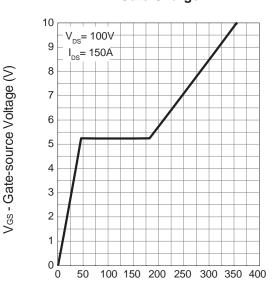
VsD - Source-Drain Voltage (V)

#### Capacitance



V<sub>DS</sub> - Drain - Source Voltage (V)

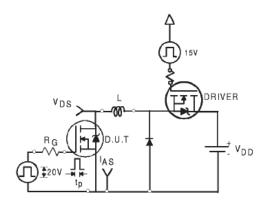
#### **Gate Charge**

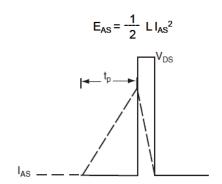


Q<sub>G</sub> - Gate Charge (nC)

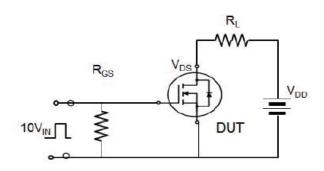


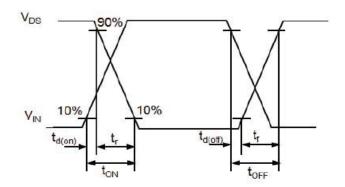
### **Avalanche Test Circuit**



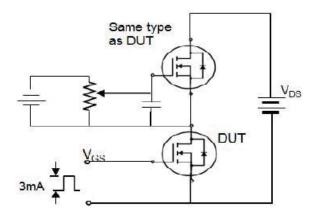


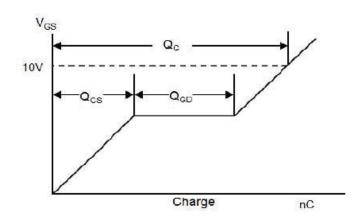
## **Switching Time Test Circuit**





# **Gate Charge Test Circuit**





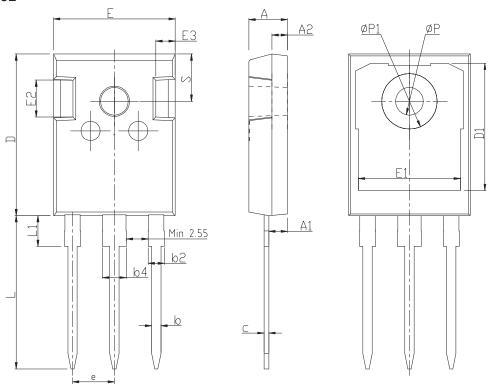


## **Device Per Unit**

Package Type	Unit	Quantity
TO-247A-3L	Tube	30

# **Package Information**

### TO-247A-3L



### COMMON DIMENSIONS

CAMBOI		mm	
SYMBOL	MIN	NOM	MAX
A	4.80	5.00	5. 20
A1	2. 21	2.41	2.61
A2	1.85	2.00	2. 15
b	1.11	1.21	1.36
b2	1.91	2.01	2.21
b4	2.91	3. 01	3. 21
С	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16. 25	16.55	16.85
Е	15.50	15.80	16. 10
E1	13.00	13.30	13.60
E2	4.80	5.00	5. 20
E3	2.30	2.50	2.70
е		5. 44BSC	
L	19.62	19.92	20. 22
L1	_	_	4.30
Р	3.40	3.60	3.80
P1	_	_	7.30
S		6. 15BSC	

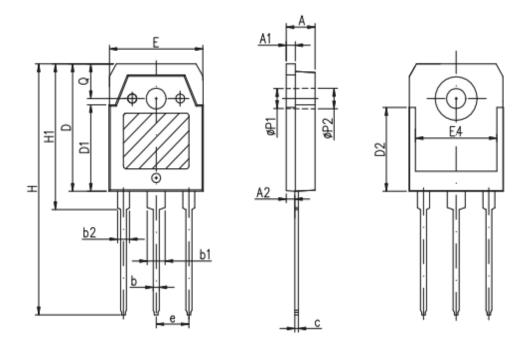


## **Device Per Unit**

Package Type	Unit	Quantity
TO-3P-3L	Tube	30

# Package Information

TO-3P-3L

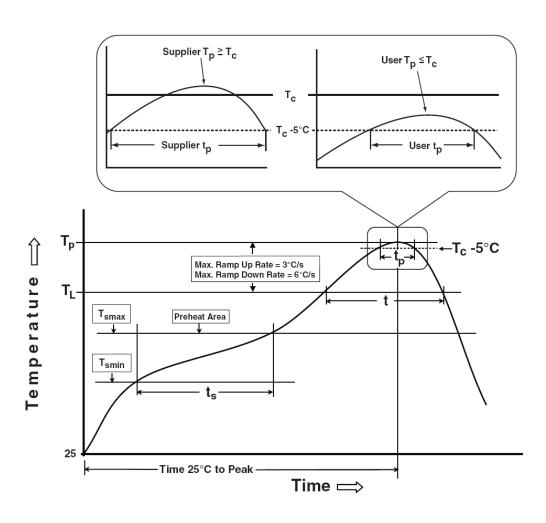


COMMON DIMENSIONS

SYMBOL		mm	
SIMDUL	MIN	NOM	MAX
A	4.60	4.80	5.00
A1	1.40	1.50	1.65
A2	1.18	1.38	1.58
b	0.80	1.00	1.20
b1	2.80	3.00	3.20
b2	1.80	2.00	2.20
c	0.50	0.60	0.75
D	19.60	19.90	20. 20
D1	13. 55	13.90	14. 25
D2		12.90	REF
Е	15. 35	15.60	15. 85
E4	12.60	ı	_
e		5.45	TYP
Н	40.10	40.50	40. 90
H1	23. 15	23. 40	23. 65
ФР1		3.20	REF
ФР2		3.50	REF



## **Classification Profile**



## **Classification Reflow Profiles**

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T <sub>smax</sub> to T <sub>P</sub> )	3 °C/second max.	3°C/second max.
Liquidous temperature (T <sub>L</sub> ) Time at liquidous (t <sub>L</sub> )	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T <sub>p</sub> )*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t <sub>P</sub> )** within 5°C of the specified classification temperature (T <sub>c</sub> )	20** seconds	30** seconds
Average ramp-down rate (T <sub>p</sub> to T <sub>smax</sub> )	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

<sup>\*</sup> Tolerance for peak profile Temperature  $(T_p)$  is defined as a supplier minimum and a user maximum. \*\* Tolerance for time at peak profile temperature  $(t_p)$  is defined as a supplier minimum and a user maximum.

### HY5012W/A



Table 1. SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process - Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> 350-2000	Volume mm <sup>3</sup> >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

## **Reliability Test Program**

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168 Hrs /500 Hrs /1000 Hrs, Bias @ 150°C
PCT	JESD-22, A102	96Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

#### **Customer Service**

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